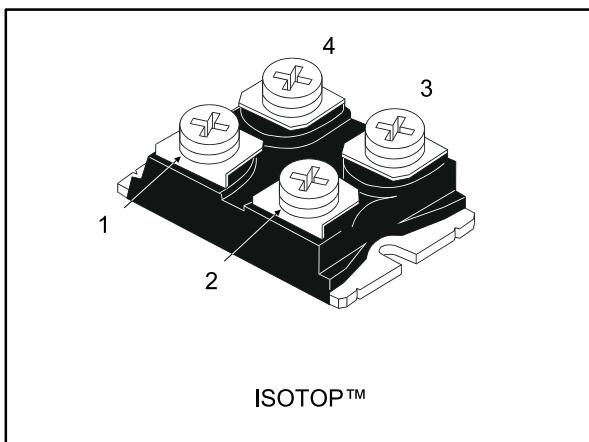
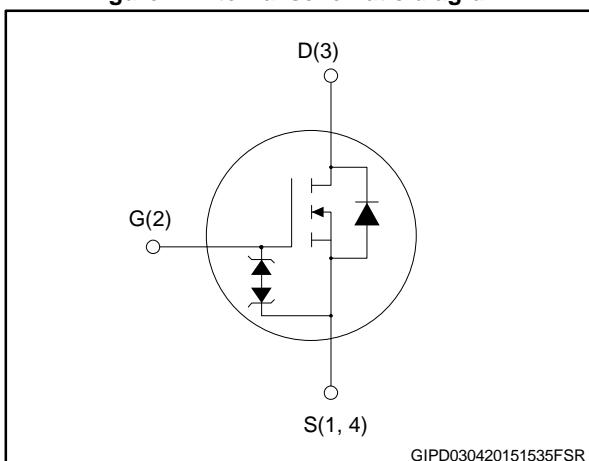


## N-channel 600 V, 0.037 Ω typ., 70 A MDmesh™ DM2 Power MOSFET in a ISOTOP™ package

Datasheet - target specification



**Figure 1: Internal schematic diagram**



### Features

Order code	V <sub>DS</sub> @ T <sub>jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STE70N60DM2	650 V	0.042 Ω	70 A

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance R<sub>DS(on)</sub>
- 100% avalanche tested
- Extremely high dv/dt and avalanche capabilities
- Zener-protected

### Applications

- Switching applications

### Description

This high voltage N-channel Power MOSFET is part of the MDmesh DM2 fast recovery diode series. It offers very low recovery charge and time (Q<sub>rr</sub>, t<sub>rr</sub>) combined with low R<sub>DS(on)</sub>, rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

**Table 1: Device summary**

Order code	Marking	Packages	Packaging
STE70N60DM2	70N60DM2	ISOTOP	Tube

## Contents

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# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate- source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	70	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	44	A
$I_{DM}^{(1)}$	Drain current (pulsed)	280	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	494	W
$I_{AR}$	Max current during repetitive or single pulse avalanche (pulse width limited by $T_{JMAX}$ )	10	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{V}$ )	1500	mJ
$dv/dt^{(2)}$	Peak diode recovery voltage slope	40	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	50	V/ns
$V_{ISO}$	Isolation withstand voltage applied between each pin and heatsink plate (AC voltage, $t = 60\text{ s}$ )	2500	V
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150	$^\circ\text{C}$

**Notes:**

(1)Pulse width limited by safe operating area.

(2) $|I_{SD}| \leq 68\text{ A}$ ,  $di/dt = 400\text{ A}/\mu\text{s}$ ,  $V_{DD} = 400\text{ V}$ ,  $V_{DS}(\text{peak}) < V_{(\text{BR})DSS}$ .(3) $V_{DS} \leq 480\text{ V}$ 

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.253	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	30	$^\circ\text{C}/\text{W}$

## 2 Electrical characteristics

( $T_c = 25^\circ\text{C}$  unless otherwise specified)

**Table 4: On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	600			V
$I_{\text{DSS}}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 600 \text{ V}$			10	$\mu\text{A}$
		$V_{DS} = 600 \text{ V},$ $T_c = 125^\circ\text{C}$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 25 \text{ V}$			$\pm 5$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3	4	5	V
$R_{DS(\text{on})}$	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}, I_D = 34 \text{ A}$		0.037	0.042	$\Omega$

**Table 5: Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$ $V_{GS} = 0$	-	5500	-	pF
$C_{oss}$	Output capacitance		-	250	-	pF
$C_{rss}$	Reverse transfer capacitance		-	3	-	pF
$C_{oss,\text{eq}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0 \text{ to } 480 \text{ V}$	-	430	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	2	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 68 \text{ A},$ $V_{GS} = 10 \text{ V}$ See <a href="#">Figure 3: "Gate charge test circuit"</a>	-	120	-	nC
$Q_{gs}$	Gate-source charge		-	25	-	nC
$Q_{gd}$	Gate-drain charge		-	60	-	nC

**Notes:**

<sup>(1)</sup> $C_{oss,\text{eq}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 6: Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{on})}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 34 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ See <a href="#">Figure 2: "Switching times test circuit for resistive load"</a>	-	17	-	ns
$t_r$	Rise time		-	16	-	ns
$t_{d(\text{off})}$	Turn-off delay time		-	86	-	ns
$t_f$	Fall time		-	10.5	-	ns

Table 7: Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		70	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		280	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 70 \text{ A}, V_{GS} = 0$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 68 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$ See <i>Figure 4: "Test circuit for inductive load switching and diode recovery times"</i>	-	145		ns
$Q_{rr}$	Reverse recovery charge	$I_{SD} = 68 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}, T_j = 150 \text{ }^\circ\text{C}$ See <i>Figure 4: "Test circuit for inductive load switching and diode recovery times"</i>	-	0.76		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	10.5		A
$t_{rr}$	Reverse recovery time		-	250		ns
$Q_{rr}$	Reverse recovery charge		-	2.6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	21		A

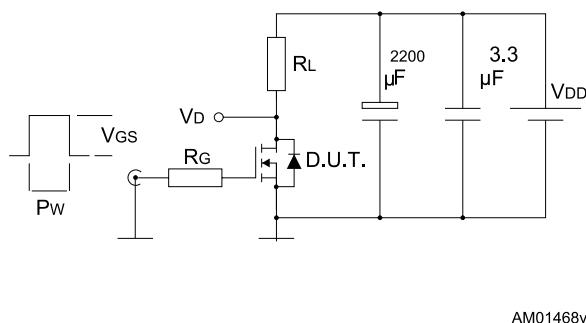
**Notes:**

(1)Pulse width limited by safe operating area.

(2)Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

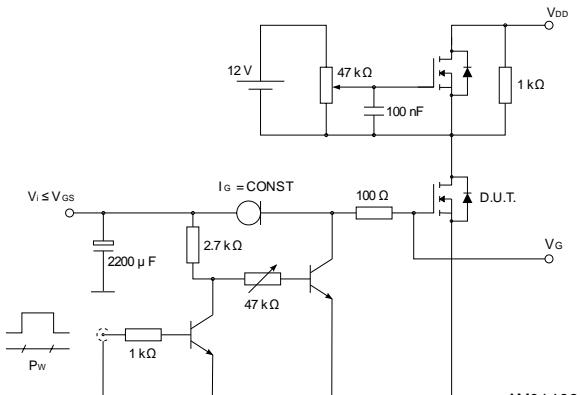
### 3 Test circuits

**Figure 2: Switching times test circuit for resistive load**



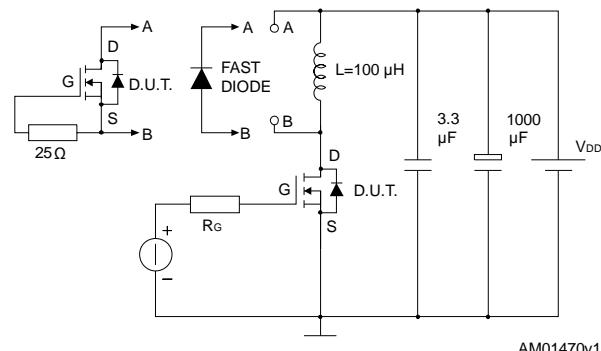
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**Figure 3: Gate charge test circuit**



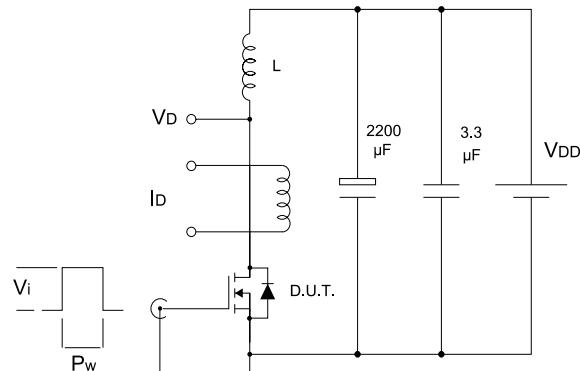
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**Figure 4: Test circuit for inductive load switching and diode recovery times**



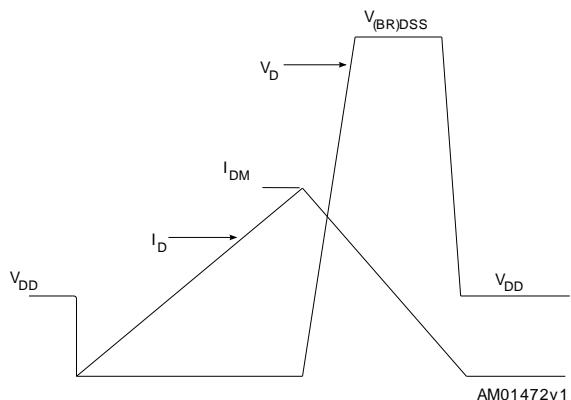
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**Figure 5: Unclamped inductive load test circuit**



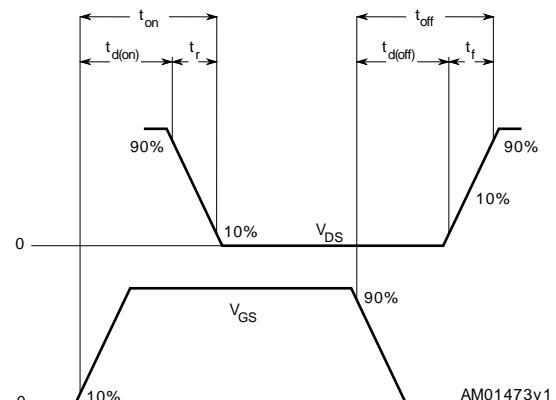
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**Figure 6: Unclamped inductive waveform**



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**Figure 7: Switching time waveform**



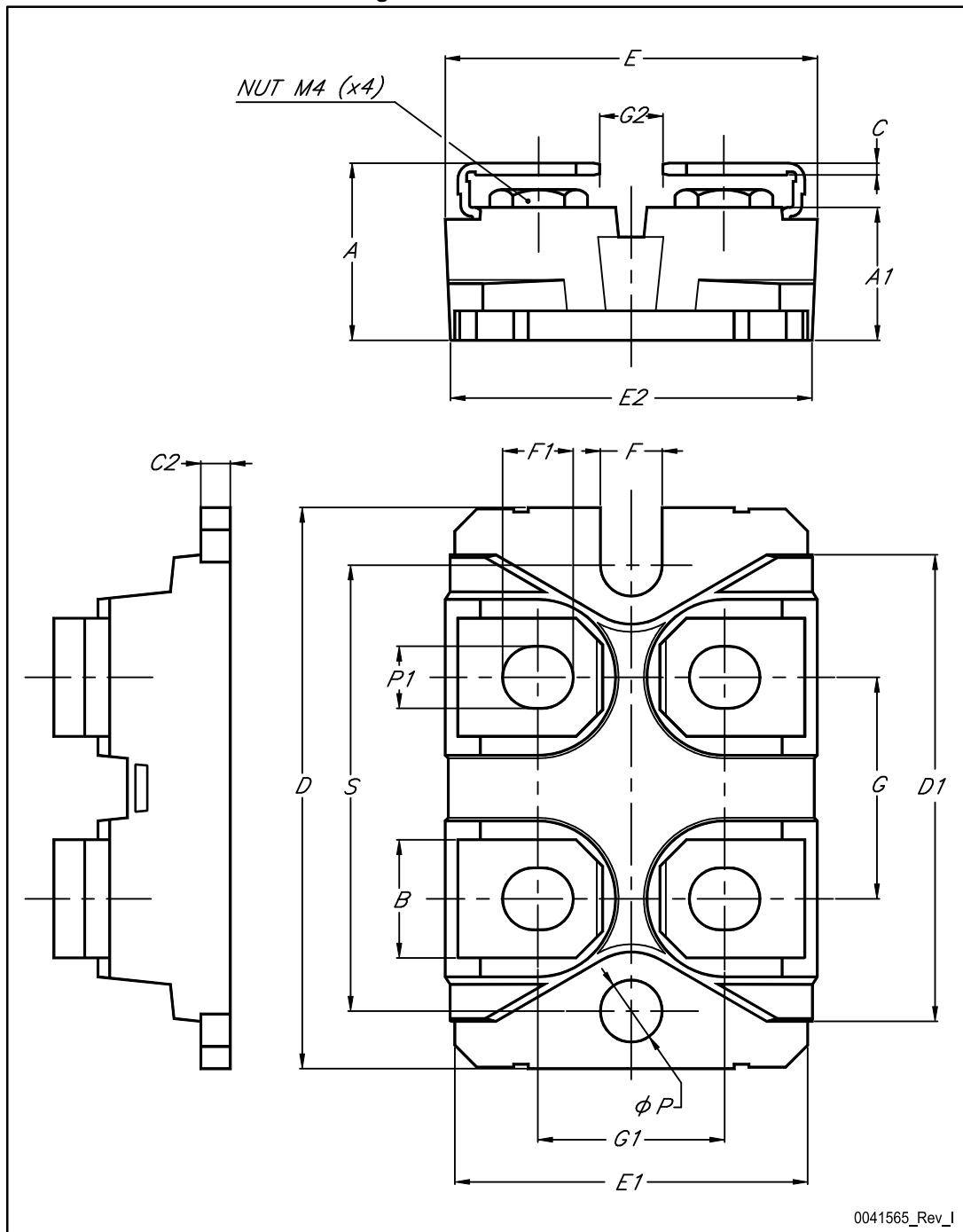
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## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

## 4.1 ISOTOP package information

Figure 8: ISOTOP outline



0041565\_Rev\_I

Table 8: ISOTOP mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	11.80		12.20
A1	8.90		9.10
B	7.80		8.20
C	0.75		0.85
C2	1.95		2.05
D	37.80		38.20
D1	31.50		31.70
E	25.15		25.50
E1	23.85		24.15
E2		24.80	
G	14.90		15.10
G1	12.60		12.80
G2	3.50		4.30
F	4.10		4.30
F1	4.60		5
ØP	4		4.30
P1	4		4.40
S	30.10		30.30

## 5 Revision history

Table 9: Document revision history

Date	Revision	Changes
03-Apr-2015	1	Initial release.

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